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IAP20 REGISTRATION 10 DEC 2005

UNITED STATES PATENT AND TRADEMARK OFFICE

Examiner:

Group:

Attorney Docket # 3521

Applicant(s) : HACHTEL, H., ET AL

Serial No. :

Filed :

For : METHOD FOR DETERMINING THE THICKNESS OF  
A LAYER...

SIMULTANEOUS AMENDMENT

December 19, 2005

Honorable Commissioner of Patents and Trademarks  
Washington, D.C. 20231

S I R S:

Simultaneously with filing of the above identified application  
please amend the same as follows:

In the Claims:

Amended claims attached hereto.